

<b>Notice of References Cited</b>		Application/Control No. 10/550,395	Applicant(s)/Patent Under Reexamination SUNAGAWA ET AL.	
		Examiner /Mark L. Berch/	Art Unit 1624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,223,038 A	09-1980	Smale, Terence C.	514/210.1
*	B	US-4,350,703 A	09-1982	Dickinson et al.	514/210.09
*	C	US-4,429,128 A	01-1984	Rosati, Robert L.	540/302
*	D	US-4,464,299 A	08-1984	Uyeo, Shoichiro	540/302
*	E	US-4,536,335 A	08-1985	Kim et al.	540/350
*	F	US-5,034,385 A	07-1991	DiNinno et al.	514/80
*	G	US-5,055,463 A	10-1991	Greenlee et al.	514/210.09
*	H	US-5,869,477 A	02-1999	Lee et al.	514/210.09
*	I	US-7,115,595 B2	10-2006	Sunagawa et al.	514/210.09
*	J	US-7,205,291 B2	04-2007	Sunagawa et al.	514/210.09
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

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